

Search Notes

Application/Control No.

09/664,565

Examiner

Hanh Nguyen

Applicant(s)/Patent under
Reexamination

NAIK, TEJAS

Art Unit

2662

SEARCHED

Class	Subclass	Date	Examiner
370	238	6/10/2005	HN
	395.1		
	392		
	400		
	396		
	397		
	216		
	218		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	6/10/2005	HN